

Maximum Ratings (@T_A = +25°C, unless otherwise specified.)

Characteristic			Symbol	Value	Units	
Drain-Source Voltage			V_{DSS}	60	V	
Gate-Source Voltage			V_{GSS}	±20	V	
Continuous Drain Current (Note 6) V _{GS} = 10V	Steady State	T _A = +25°C T _A = +70°C	I _D	3.3 2.6	А	
	t<10s	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	4.1 3.4	Α	
Maximum Continuous Body Diode Forward Current (Note 5)			I _S	2.0	Α	
Pulsed Drain Current (10µs pulse, duty cycle = 1%)			I _{DM}	12	Α	
Avalanche Current (Note 7) L=0.1mH			I _{AS}	10	Α	
Avalanche Energy (Note 7) L=0.1mH			E _{AS}	5.9	mJ	

Thermal Characteristics (@T_A= +25°C, unless otherwise specified.)

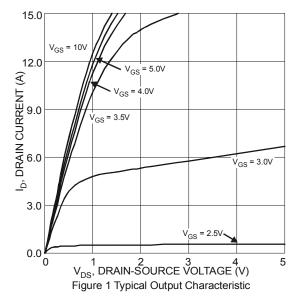
Characteristic		Symbol	Value	Units	
Total Power Dissipation (Note 5)		P_{D}	1.2	W	
Thermal Resistance, Junction to Ambient (Note 5)	Steady State		104	°C/W	
Thermal Resistance, Junction to Ambient (Note 5)	t<10s	$R_{\theta JA}$	61		
Total Power Dissipation (Note 6)		P_{D}	1.5	W	
Thermal Peciatones, Junction to Ambient (Note 6)	Steady State	Ъ	83	°C/W	
Thermal Resistance, Junction to Ambient (Note 6)	t<10s	$R_{\theta JA}$	50		
Thermal Resistance, Junction to Case		$R_{\theta JC}$	14.5		
Operating and Storage Temperature Range		$T_{J_i}T_{STG}$	-55 to +150	°C	

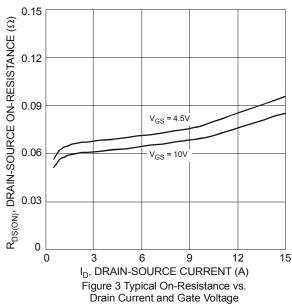
$\textbf{Electrical Characteristics} \ (@T_A = +25^{\circ}C, \ unless \ otherwise \ specified.)$

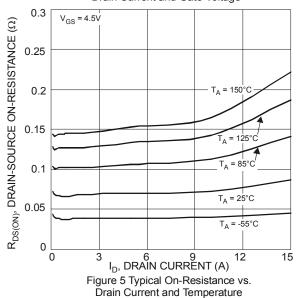
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 8)							
Drain-Source Breakdown Voltage	BV _{DSS}	60	_		V	$I_D = 250 \mu A, V_{GS} = 0 V$	
Zero Gate Voltage Drain Current	I _{DSS}	_	_	1	μΑ	V _{DS} = 60V, V _{GS} = 0V	
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	V _{GS} = ±16V, V _{DS} = 0V	
ON CHARACTERISTICS (Note 8)							
Gate Threshold Voltage	V _{GS(th)}	1.0	_	3.0	V	I_D = 250 μ A, V_{DS} = V_{GS}	
Statio Dunin Source On Benintanna			68	80	mΩ	V _{GS} = 10V, I _D = 4.5A	
Static Drain-Source On-Resistance	R _{DS} (ON)	_	70	100		V _{GS} = 4.5V, I _D = 3.5A	
Diode Forward Voltage	V_{SD}	_	0.75	1.1	V	I _S = 12A, V _{GS} = 0V	
DYNAMIC CHARACTERISTICS (Note 9)							
Input Capacitance	C _{iss}		588			V _{DS} = 30V, V _{GS} = 0V f= 1MHz	
Output Capacitance	Coss	_	26.5	_	pF		
Reverse Transfer Capacitance	Crss	_	20	_			
Gate Resistance	R_g	_	1.5	_	Ω	Vgs= 0V, Vds= 0V, f=1MHz,	
Total Gate Charge (V _{GS} = 4.5V)	Q_g	_	5.6	_		V - 20V I - 2A	
Total Gate Charge (V _{GS} = 10V)	Qg	_	12.3	_	~C		
Gate-Source Charge	Q_{gs}	_	1.7	_	nC	$V_{DS} = 30V, I_{D} = 3A$	
Gate-Drain Charge	Q _{gd}	_	1.9	_			
Turn-On Delay Time	t _{D(on)}	_	3.5	_		V_{DD} = 30V, V_{GS} = 10V $R_L \cong 50\Omega$, $R_G \cong 20\Omega$	
Turn-On Rise Time	t _r	_	4.1	_	nS		
Turn-Off Delay Time	t _{D(off)}	_	35	_	no		
Turn-Off Fall Time	t _f	_	11	_			
Body Diode Reverse Recovery Time	trr	_	18	_	nS	I _S = 12A, dI/dt = 100A/μs	
Body Diode Reverse Recovery Charge	Qrr	_	12	_	nC	I _S = 12A, dI/dt = 100A/µs	

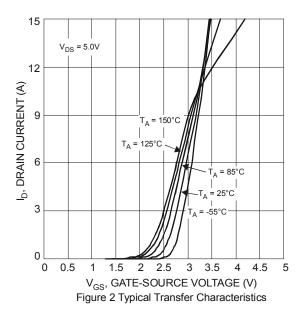
5. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout. 6. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate. 7. I_{AS} and E_{AS} rating are based on low frequency and duty cycles to keep T_{J} = +25°C. 8. Short duration pulse test used to minimize self-heating effect. 9. Guaranteed by design. Not subject to product testing. Notes:

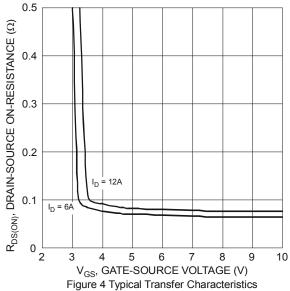


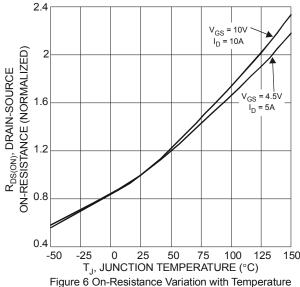




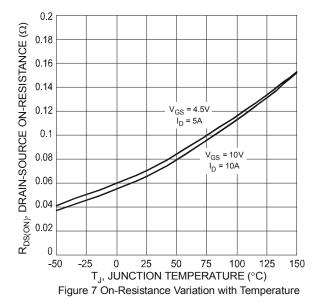


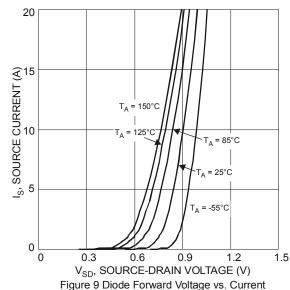


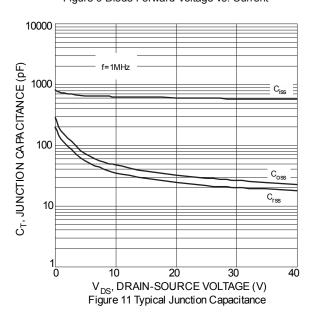












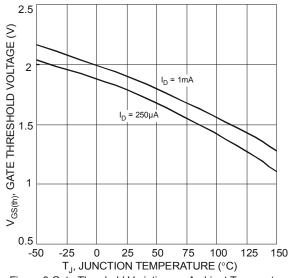
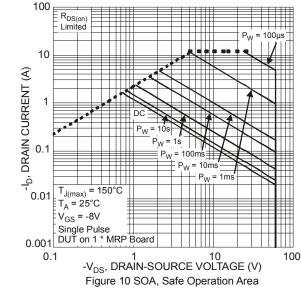
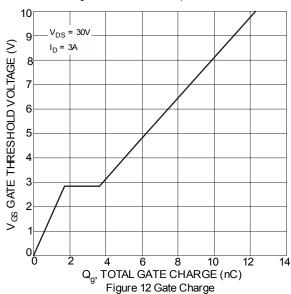


Figure 8 Gate Threshold Variation vs. Ambient Temperature







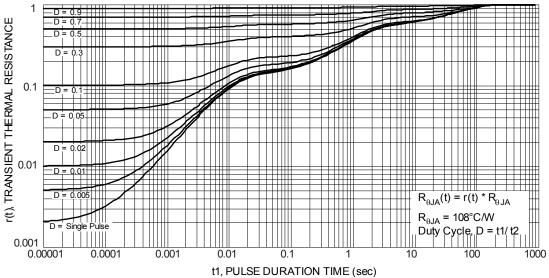
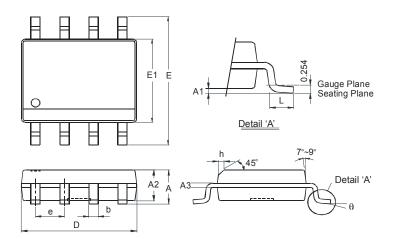


Figure 13 Transient Thermal Resistance

Package Outline Dimensions

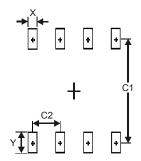
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for the latest version.



SO-8				
Dim	Min	Max		
Α	-	1.75		
A1	0.10	0.20		
A2	1.30	1.50		
А3	0.15	0.25		
b	0.3	0.5		
D	4.85	4.95		
Е	5.90	6.10		
E1	3.85	3.95		
е	1.27 Typ			
h	-	0.35		
٦	0.62	0.82		
θ	0°	8°		
All Dimensions in mm				

Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
Х	0.60
Y	1.55
C1	5.4
C2	1.27



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